

<b>Notice of References Cited</b>	Application/Control No. 10/617,742	Applicant(s)/Patent Under Reexamination YUN ET AL.	
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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,436,833 B1	08-2002	Pang et al.	438/692
	B	US-6,313,331 B1	11-2001	Cavell et al.	556/18
	C	US-6,473,186	10-2002	Kawasaki et al.	356/512
	D	US-2004/0032006 A1	02-2004	Yun et al.	257/510
	E	US-4,740,480	04-1988	Ooka, Hideyuki	438/436
	F	US-6,258,692 B1	07-2001	Chu et al.	438/400
	G	US-6,057,209	05-2000	Gardner et al.	438/427
	H	US-4,952,524	08-1990	Lee et al.	438/437
	I	US-4,871,689	10-1989	Bergami et al.	438/427
	J	US-6,756,654 B2	06-2004	Heo et al.	257/510
	K	US-4,871,689	10-1989	Bergami et al.	438/427
	L	US-2004/0266131 A1	12-2004	Kawasaki et al.	438/424
	M	US-5,702,977	12-1997	Jang et al.	216/38

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	X	

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